Facilitating Hole Transfer on Electrochemically Synthesized p-type CuAlO$_2$ Films for Efficient Solar Hydrogen Production from Water

Seung Yo Choi,$^{1,2}$ Chang-Duk Kim,$^3$ Dong Suk Han,$^4$ Hyunwoong Park$^{1,2,5,*}$

$^1$School of Energy Engineering, $^2$School of Architectural, Civil, Environmental, and Energy Engineering, and $^3$Department of Physics, Kyungpook National University, Daegu 41566, Korea

$^4$Chemical Engineering Program, Texas A&M University at Qatar, Education City, Doha, P.O. Box 23874, Qatar

$^5$Advanced Institute of Water Industry, Kyungpook National University, Daegu 41566, Korea

*To whom correspondence should be addressed (H. Park)

Tel: +82-53-950-8973; E-mail: hwp@knu.ac.kr
Figure S1. Time-profiled changes in currents during electrochemical deposition of Cu(II) and Al(III) onto FTO in water at $-0.31 \text{ V}_{\text{SCE}}$ and DMSO at $-1.91 \text{ V}_{\text{SCE}}$ for 2 h.

Figure S2. (a) XPS and (b) EDX analyses of as-synthesized CuAlO$_2$ (DMSO/Air) sample.
Figure S3. The XPS O1s spectra of CuAlO$_2$ sample.

Figure S4. EDX elemental mappings for top views (a–c) and cross-sectional views (d–f) of CuAlO$_2$ (i.e., DMSO/Air sample).
Figure S5. Time-profiled changes in photocurrents during photoelectrochemical H₂ production using CuAlO₂ electrodes at +0.3 V_RHE in aqueous KOH solutions (1 M) without and with sulfide, sulfite, or sulfide/sulfite (each 0.5 M).
Figure S6. Comparison of samples synthesized under different conditions for (a) time changes in photocurrents at +0.3 V\textsubscript{RHE} in aqueous KOH solution (1 M) containing sulfide (0.5 M) and sulfite (0.5 M), (b) H\textsubscript{2} production at +0.3 V\textsubscript{RHE}, and (c) Faradaic efficiencies for H\textsubscript{2} production at +0.3 V\textsubscript{RHE}. 
Figure S7. Comparison of light-chopped LSVs of CuAlO$_2$ under electrolyte-side and substrate-side irradiations in aqueous KOH solution (1 M) purged with N$_2$. Under the electrolyte-side irradiation, holes must travel a longer distance; under the substrate-side irradiation, electrons travel a longer distance. Considering the transmittance of the substrate (FTO), the incident light intensity decreases by ~20% under the substrate-side irradiation. See Figure S8 for a comparison of the incident light intensities under the two irradiation conditions.
Figure S8. Comparison of normalized light intensities of AM1.5 light in the absence and presence of FTO substrate in front of silicon detector.

Figure S9. Time-profiled changes in photocurrents during photoelectrochemical H₂ production using CuAlO₂ at +0.3 V_{RHE} and Au/CuAlO₂ at +0.3 V_{RHE} and +0.55 V_{RHE} in aqueous KOH solutions (1 M) purged with N₂.
Figure S10. Photoluminescence (PL) spectra of CuAlO$_2$ and Au/CuAlO$_2$ films excited at $\lambda = 379$ nm.
Figure S11. Time-resolved photoluminescence emission (400–500 nm) decay spectra of CuAlO$_2$ and Au/CuAlO$_2$. Upon excitation at $\lambda = 379$ nm, the emission decays exponentially, with the decay constants estimated by fitting the decay curves to the following equation: $I(t) = A_1\exp(-t/\tau_1) + A_2\exp(-t/\tau_2) + A_3\exp(-t/\tau_3)$, where $I(t)$ is the time-dependent photoluminescence intensity, $A$ is the normalized amplitude of the corresponding lifetime component, and $\tau$ is the photoluminescence lifetime.

<table>
<thead>
<tr>
<th>Material</th>
<th>$\tau_1$ (ns)</th>
<th>$\tau_2$ (ns)</th>
<th>$\tau_3$ (ns)</th>
<th>Average $\tau$</th>
</tr>
</thead>
<tbody>
<tr>
<td>CuAlO$_2$</td>
<td>0.048 (78.30%)</td>
<td>0.322 (15.76%)</td>
<td>1.567 (5.92%)</td>
<td>0.18</td>
</tr>
<tr>
<td>Au/CuAlO$_2$</td>
<td>0.037 (80.24%)</td>
<td>0.275 (15.04%)</td>
<td>1.469 (4.71%)</td>
<td>0.14</td>
</tr>
</tbody>
</table>
Figure S12. Time-resolved photoluminescence emission decay spectra of FTO only (w/o CuAlO$_2$) and CuAlO$_2$ (w/ CuAlO$_2$). The decay profiles were different each other, suggesting that the shortest decay lifetime component (i.e., $\tau_1$ in Figure S11) is meaningful. Then, we subtracted the IRF from the decay profiles of CuAlO$_2$ and Au/CuAlO$_2$ samples and re-fitted the obtained decay profiles. The decay lifetimes ($\tau_2$) of CuAlO$_2$ and Au/CuAlO$_2$ were estimated to be 1.706 and 1.513 ns, respectively. Although $\tau_2$ was much larger than $\tau_1$, the Au underlayer clearly decreased the decay lifetime. This decrease in $\tau$ should have resulted from the charge transfer facilitated by the Au layer, leading to a reduction in the charge recombination.